



**Good Morning!**

**Good Afternoon!**

**Good Evening!**

# 1<sup>st</sup> ODSA Chiplet Business Workshop

Ravi Agarwal

Open Domain-Specific Architecture, Chiplet  
Business Workstream lead

Technical Sourcing, Facebook



**OPEN**  
Compute  
Project®

Connect. Collaborate. Accelerate.



# THANK YOU

Workshop Sponsors:

FACEBOOK



**ASE GROUP**



Start Time	End Time	Topic
07:30	08:00	Opening Coffee Sponsorship #1
08:00	08:04	Welcome
08:04	08:08	ODSA how/what/where/why
08:08	08:32	<b>State of the art of Chiplets</b>
08:08	08:16	Need for Establishing a Chiplet Ecosystem
08:16	08:24	Chiplet business challenges for AI accelerator
08:24	08:32	HIR status update (Chiplet Business Challenges)
08:32	08:40	Business Challenges and Opportunities of Chiplets in Heterogeneous Acceleration
<b>Chiplet Value Chain Discussion Design--&gt;Build--&gt;Deliver</b>		
08:40	09:23	<b>Design</b>
08:40	08:48	Chiplets in Space
08:48	09:23	<b>Moderator: Allan</b> Synopsys: Manuel Cadence: Rishi Alphawave: Tony
09:23	09:38	Coffee Break Sponsorship #2
09:38	10:40	<b>Build</b>
09:38	09:45	Chiplet Economic constraints
09:45	10:40	<b>Moderator: Andreas</b> Samsung: Max ASE: Eelco JCET: Swami Teradyne: Regan
10:40	10:55	Coffee you Break Sponsorship #3
10:55	11:58	<b>Deliver</b>
10:55	11:03	Business consideration for Chiplet based compute products
11:03	11:58	<b>Moderator: David</b> Microchip: Anu Marvell: Ramin Google: Ben Alibaba: Weifeng FB: Nicolaas Microsoft: Ishwar



**OPEN**  
Compute  
Project®

# ODSA Business Workshop.

Bapi Vinnakota

Open Domain-Specific Architecture,  
Sub-project lead

System Architect, Broadcom



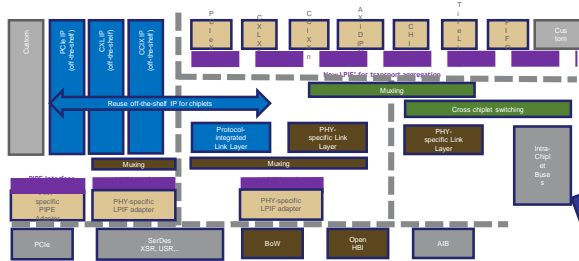


# Welcome!

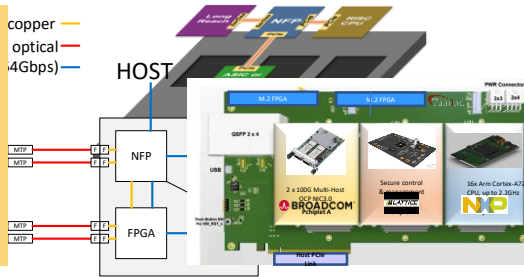
- Our biggest workshop ever!
  - HUUUUGE effort from DJ, Ravi, Rishi, many others
- After the workshop
  - Participate actively, join a work stream!
- ODSA meets Fridays at 8 AM Pacific, work streams meet weekly
  - <https://www.opencompute.org/wiki/Server/ODSA>
- Next few Fridays
  - BoW Test Chip Proposals
  - Chiplet Market Survey
  - Chiplets from LETI
  - SW PoC workshop
  - Memory

# ODSA Charter

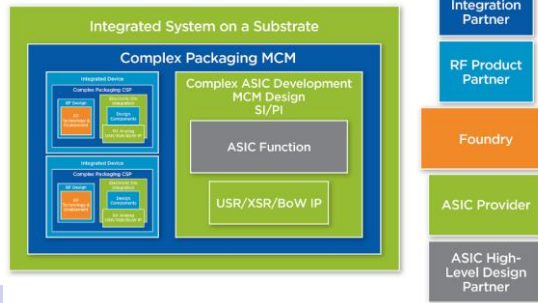
Open D2D  
Interface  
Reduce barrier to  
interoperation



Reference  
Designs  
Starting point for  
new designs



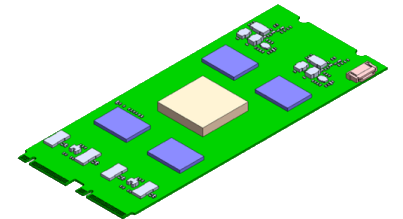
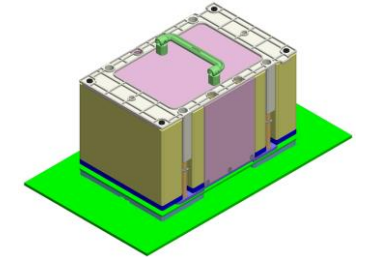
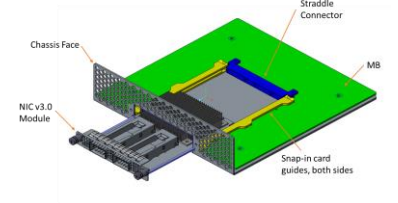
Reference  
Workflows  
Reusable, open  
practices



ODSA Activities

## Chiplet Marketplace

Integrate best-in-class  
chiplets from multiple  
vendors through open  
interfaces



OCP modular  
form factors



OCP  
GLOBAL  
SUMMIT

2020

# ODSA Workstreams

Attendance and/or participation do not imply corporate endorsement

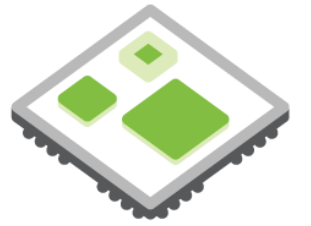
Each group meets weekly, details at <https://www.opencompute.org/wiki/Server/ODSA>

Workstream	Leader	Participants	Objective
PHY Layer	Robert Wang 	    	PCIe PIPE adapter
Bunch of Wires	Mark Kuemerle 	     	Low cost D2D PHY
CDX	Jawad Nasrullah 	    	Chiplet design exchange
Biz 9 AM Fridays	Ravi Agarwal 	    	Chiplet workflowP
PoC hardware	JP Balachandran 	   	PoC board design
PoC software	Kevin Drucker 	    	Application/Infra software
Link layer	Open 	    	ODSA Stack
OpenHBI	Kenneth Ma 	    	High perf D2D PHY
End user	Dharmesh Jani	   	
BoW Test Chip		Sub-project lead: Bapi Vinnakota 	



# Please Help, Join Us!

- Join a work stream, each meets weekly
- Help with the PoC, software, use case dev,
- Review, help complete documents in flight
- Need packaging and test definition and work streams
- Make chiplets with, IP for, the open ODSA stack
- <https://www.opencompute.org/wiki/Server/ODSA>



OPEN DOMAIN  
SPECIFIC  
ARCHITECTURE



SERVER



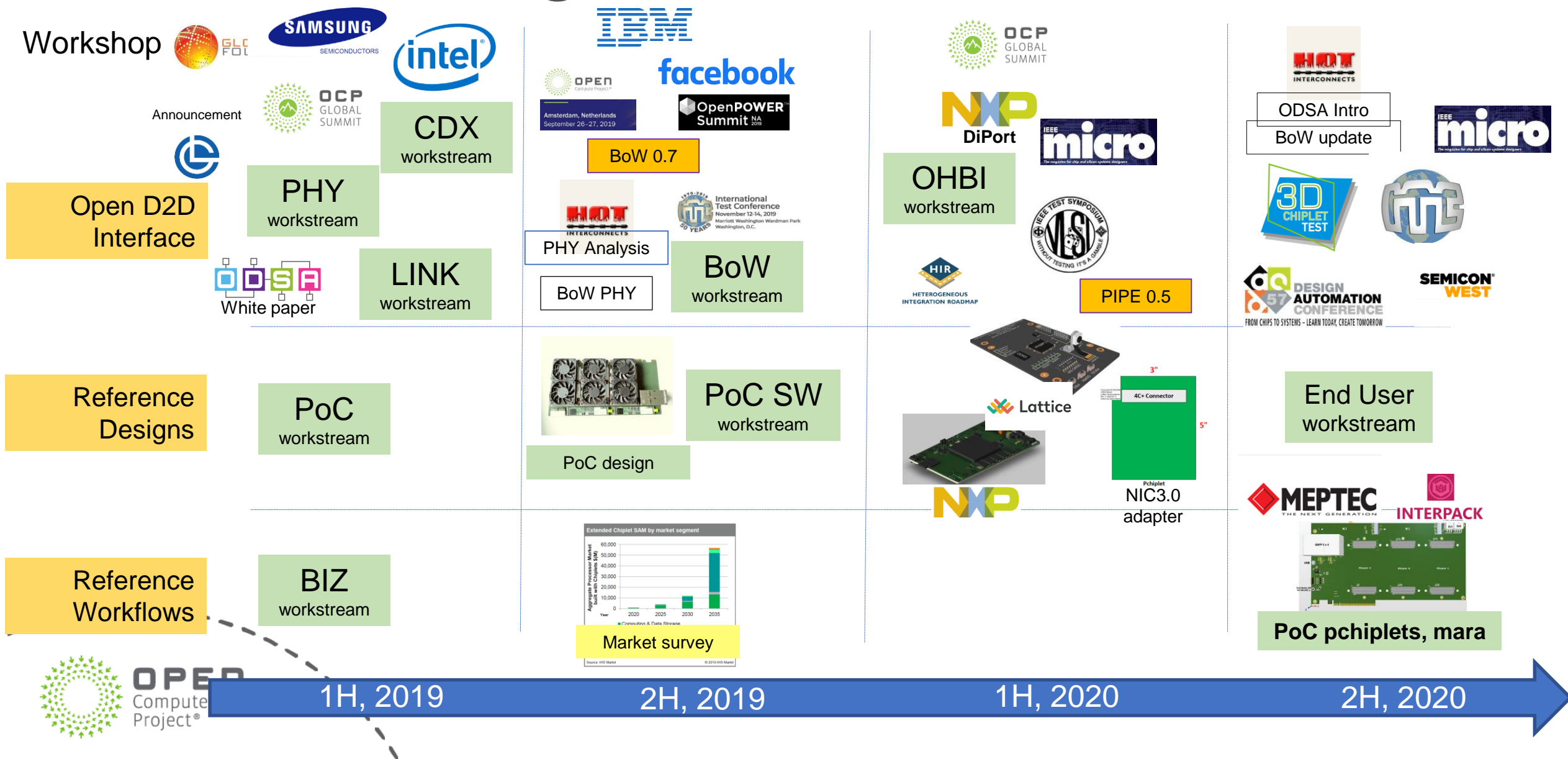
**OPEN**  
Compute  
Project®

# Reference

Connect. Collaborate. Accelerate.

# ODSA Progress

details at <https://www.opencompute.org/wiki/Server/ODSA>





# For More Information

[ODSA Wiki](#): All workshops, minutes of weekly calls, workstreams (open access)

## Specification proposals:

Bunch of Wires [GitHub repo](#) (open access)

[PIPE adapter](#) (PCIe over D2D), [DiPort](#) (AXI over D2D) (open, but need to request access)

[ODSA PoC Demo](#) (open access), [ODSA PoC Implementation Specification](#) (open, but need to request access)

## In-flight

LPIF, LPIF' proposal

ODSA PoC SW

Open HBI specification (needs CLA)

## Technical Papers/Talks

[ODSA white paper](#), ODSA Wiki

R. Farjadrad, M. Kuemerle, B. Vinnakota, "A Bunch-of-Wires (BoW) Interface for Interchiplet Communication", IEEE Micro, Jan. 2020

G. Taylor, R. Farjadrad, B. Vinnakota, "High Capacity On-Package Physical Link Considerations", Hot Interconnects, Aug. 2019

D. Jani, "Musings on Domain Specific Accelerators, Open Compute Project and Cambrian Explosion", LinkedIn

M. Hutner, et al "Test Challenges in a Chiplet Marketplace", VLSI Test Symposium, Apr. 2020

B. Vinnakota, "The Open Domain-Specific Architecture: An Introduction", Design Automation Conference, July. 2020

D. Ratchkov, J. Nasarullah, "Power Modeling in Chiplets", Design Automation Conference, July. 2020

S. Ardalan et al, "Bunch of Wires PHY: An Open D2D Interface", Hot Interconnect 2020

K. Drucker et al, "The Open Domain-Specific Architecture", Hot Interconnect 2020

S. Ardalan et al, "Bunch of Wires Interface: Interchiplet Link Testing and Loopback", 7<sup>th</sup> Int. Workshop on 3D and Chiplet Test, Nov 2020

S. Ardalan et al, "Bunch of Wires PHY: An Open D2D Interface", IEEE Micro 2021

B. Vinnakota et al, "The Open Domain-Specific Architecture", IEEE Micro 2021

ODSA track at the OCP Global Tech Summit.

# Need for Establishing a Chiplet Ecosystem

Javier DeLaCruz, ARM

Connect. Collaborate. Accelerate.



**OPEN**  
Compute  
Project®

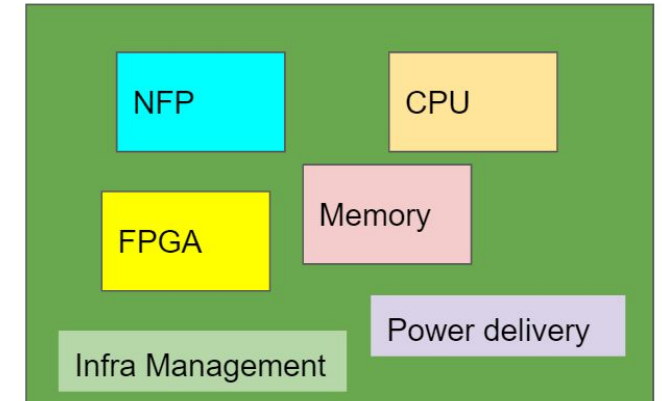


# What is a Chiplet?

A Chiplet is defined by having an **interface** optimized for die-to-die connectivity within a package

A Chiplet lacks the drive strength to be packaged independently

Ideally this creates a system that is more efficient than using conventional die or packaged parts



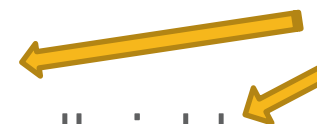
Mara, ODSA idealized chiplet concept



# Drivers and Barriers of Chiplets

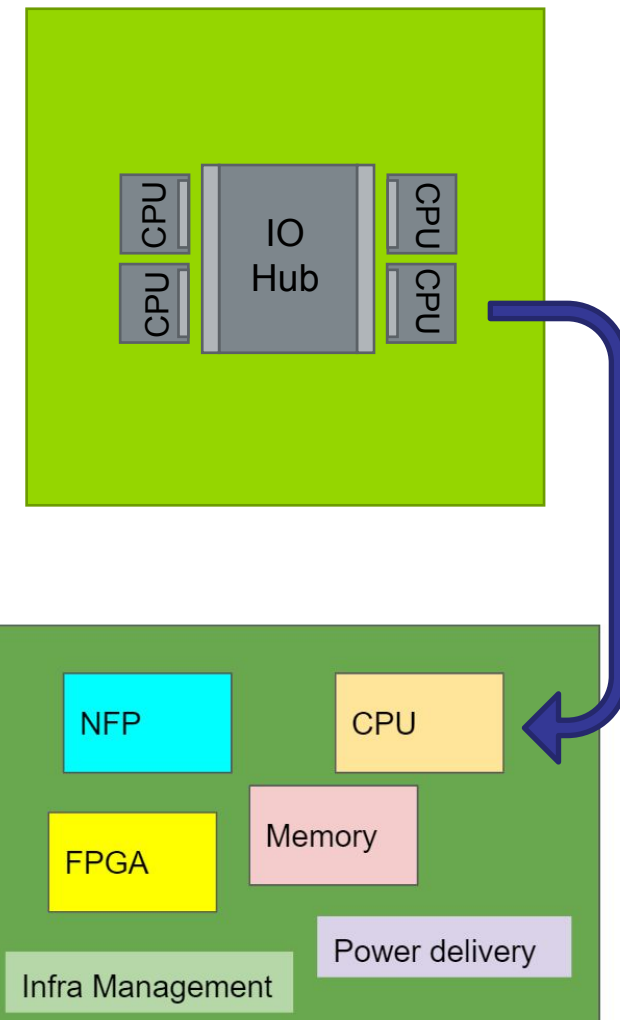
- Three main drivers exist for chiplets
  - Reticle Limits, needing more silicon area
  - Cost Savings, partition die to improve overall yield
  - **Heterogeneity**
- Barriers for Heterogeneity
  - Tapeout costs for each chiplet
  - Starting from scratch may not be practical
  - Common interface standards (phy, control, etc.)
  - Worst case interconnect pitch may drive package technology
  - Lack of chiplet marketplace and data (testability, thermal, pitch, interfaces, software, yield coverage, etc.)
  - Who owns chiplet inventory, yield, etc? (not an issue for vertical integration)

Vertically  
Integrated



# It Takes a Village

- Create elements with community reusability in mind
- Not all elements need advanced nodes
- It is likely that at least one device is custom (or an FPGA) and that will tie elements together
- IP vendors likely need to work with partners to market chiplets
- Many chiplet needs in voltage regulation, CPU, memory, etc.
- Opportunity for marketplace development in the industry



Mara, ODSA idealized chiplet concept

# Thank You

Connect. Collaborate. Accelerate.







# Chiplet business challenges for AI accelerators

Arvind Kumar  
IBM Research  
ODSA March 2021 Business Workshop

Connect. Collaborate. Accelerate.

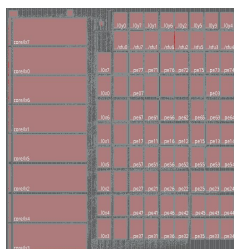


**OPEN**  
Compute  
Project®

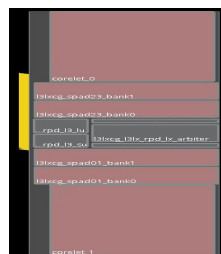


# IBM Research PoV on Chiplet Value Proposition

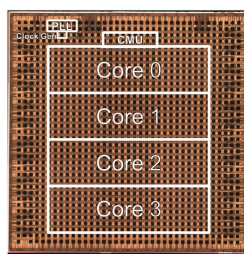
- IBM Research has developed an AI core optimized for DNN processing



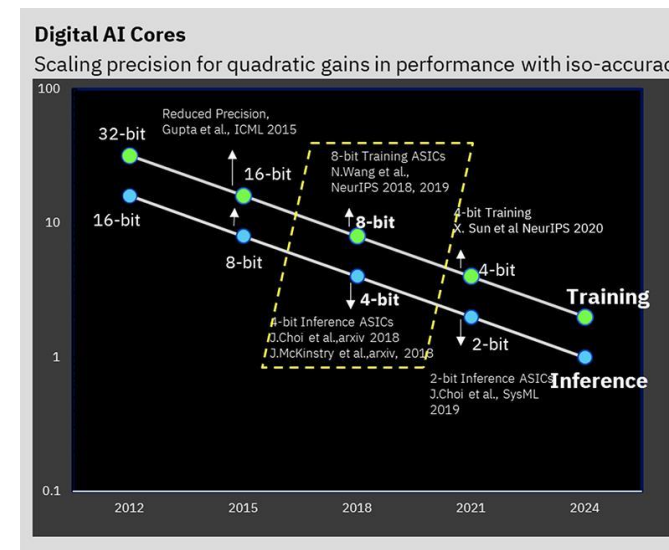
Gen 1  
VLSI 2018



Gen 2  
VLSI 2020



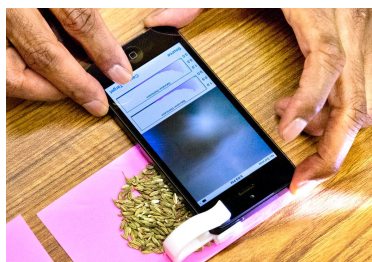
Gen 3  
ISSCC 2021



- Many diverse use cases with varying core count, core functionality, memory, power envelope requirements.
  - New SoC for each new application not possible
- Value proposition of Chiplet-based ecosystem: Enable right-sized, modular solutions, integrating AI compute, I/O, and memory chiplets.

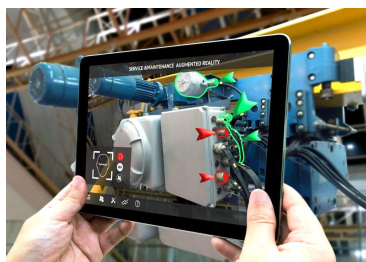
# Different Use Cases have Different Requirements

IoT / Sensor



< 100 mW  
1-5 cores

Mobile



250 mW to <2W

Automotive



20-50W

Data Center



75-300W  
Tens to hundreds of cores



<b>AI workloads</b>	Mainly inference	Training and inference
<b>Core count</b>	Small	Large (even larger for training!)
<b>Technology</b>	Low power/older node	High performance/leading node
<b>Power envelope</b>	Low	High
<b>Latency / throughput</b>	Latency critical	Both may be important
<b>Packaging</b>	Low cost	Advanced packaging to support high BW

**Chiplets: Composability and Scalability solution for wide variety of use cases**  
(networks, precision, memory, power envelope)

# Chiplet Business Challenges

## Design Challenges: Prototyping and Design Tools

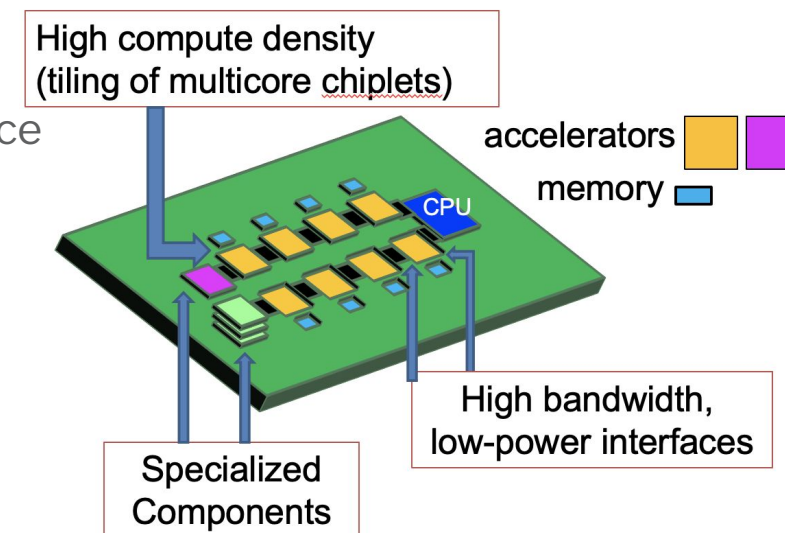
- End-user applications constantly evolving:  
New AI Workloads with new networks and different compute/memory balance
- Need for rapid research prototyping of new AI cores (e.g., reuse nest)
- Chiplet+Package+PCB co-design EDA
  - ❖ Standardization of input/output formats across tools
  - ❖ Tools to support full implementation/verification flows (including complex CPI, thermal, etc.)

## Build Challenges: Support for broad variety of IP in chiplet format (memory, I/O, accelerators)

- Open standards for I/O interfaces
- Interfaces and Packaging that can meet latency/bandwidth/power/thermal requirements

## Deliver Challenges: Multi-vendor flexibility in supply chain

- Interoperability of silicon, package, assembly, test companies and methods to enable flexibility of chiplets and packaging options







# Chiplet Business Challenges

A Perspective from Heterogeneous Integration  
Roadmap (HIR)

March 12<sup>th</sup> , 2021

William (Bill) Chen

ASE Group

In Collaboration with Heterogeneous Integration Roadmap (HIR) Technical Working Groups Team



Connect. Collaborate. Accelerate.





# Heterogeneous Integration Roadmap(HIR) Chapters

## Covering the total Microelectronics Systems Ecosystem

### System & Market Applications

- High Performance Computing & Data Center
- Mobile
- Medical, Health & Wearables
- Automotive
- IoT
- Aerospace & Defense

### Co-Design + Simulation

- Co-Design
- Co-Simulation

### Integration Processes

- SiP & Module
- 3D +2D & Interconnect
- WLP (fan in and fan out)

### Building Blocks

- Single & Multi Chip Integration + Substrate
- Integrated Photonics
- Integrated Power Electronics
- MEMS & Sensor integration
- 5G Communication & Beyond

### Cross Cutting Technologies

- Materials & Emerging Res Materials
- Emerging Research Devices
- Test
- Supply Chain
- Security
- Thermal Management

# HIR 4<sup>th</sup> Annual Conference Feb 24 – 26, 2021

## Day 1 Symposium – Day 2 & 3 Cross TWG Workshop

- **Symposium – 6 Plenary Speaker - - Vision on Heterogeneous Future**
  - “Future of Microelectronics after the Pandemic” Ajit Manocha President & CEO SEMI
  - “21<sup>st</sup> Century Nano System for Abundant-Data Computing”, Subhasish Mitra, Stanford University
  - “Reimagining Co-Design of HPC Systems for a Heterogeneous Future” John Shalf, LBL
  - “Accelerating Electronics & Photonics Innovations for Revolutionary Microsystems” Gordon Keeler DARPA
  - “Thermal Sciences for the Heterogeneous Future” Ken Goodson, Dept., Stanford University
  - “Charge to Heterogeneous Integration Roadmap Teams” Nicky Lu, CEO & Founder, Etron Technology Taiwan
- **Cross TWG Workshop**
  - 8 min presentation from all 22 TWG teams
  - Invited Chiplet speakers: Raja Swaminathan (AMD) & Bapi Vinnokota (ODSA/OCP & Broadcom)
  - SRC Program Director John Oakley on Heterogeneous Integration Science Programs
  - Cross TWG Workshop Value Proposition – The Whole of HIR Roadmap greater than the Sum of individual Chapters
- **Recorded 3 Days Video available.** <https://ieee-region6.org/scv-eps/?p=2416>

# Accelerating Electronics and Photonics Innovation for Revolutionary Microsystems

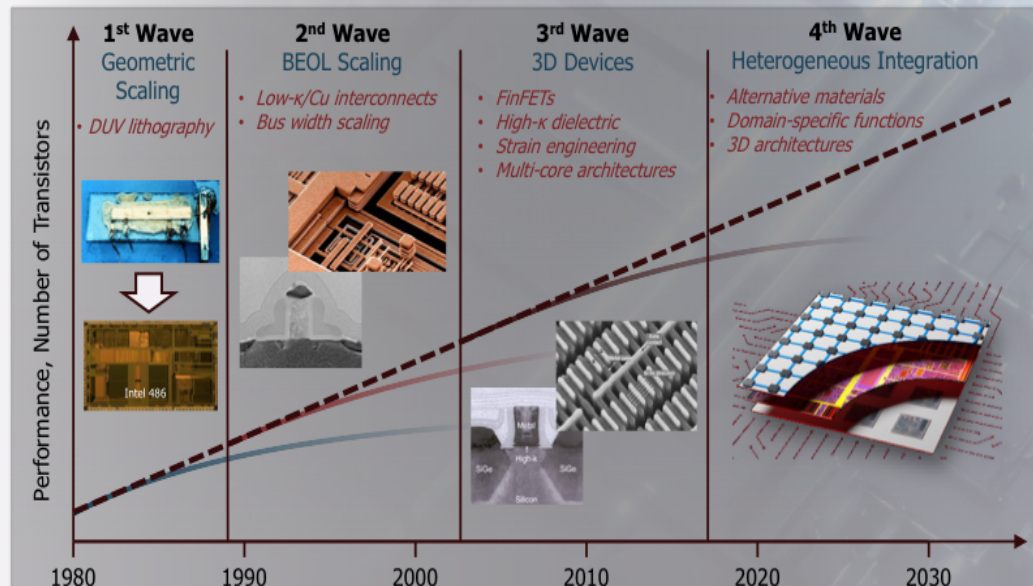
Dr Gordon Keeler

**DARPA**

February 24, 2021

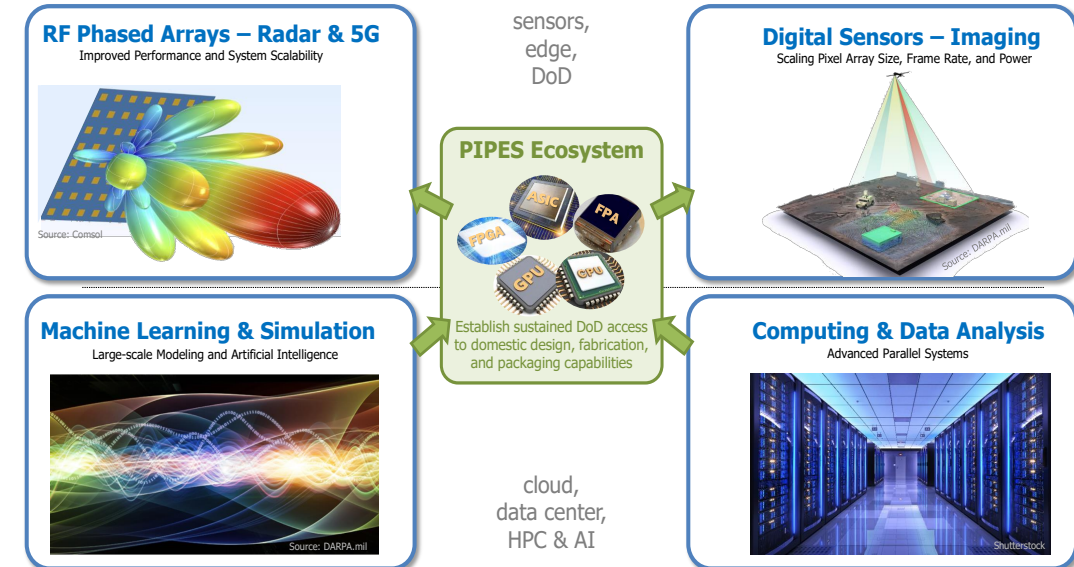
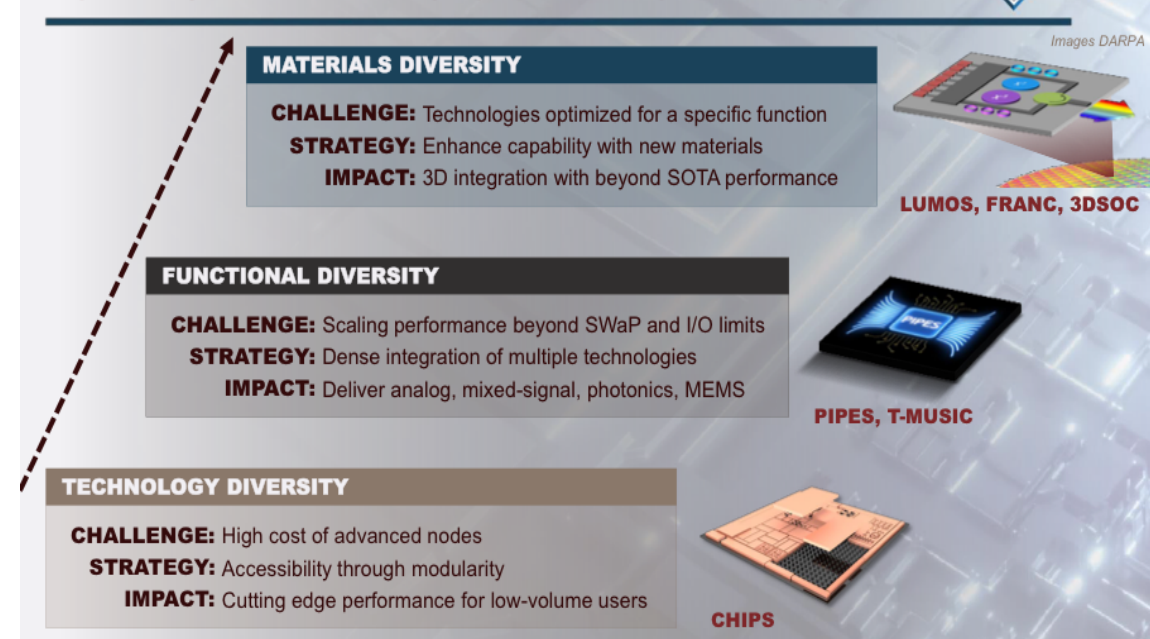
## HETEROGENEOUS INTEGRATION

Extending Moore's law and broadening our impact



Video available. <https://ieee-region6.org/scv-eps/?p=2416>

## DISTINCT DRIVERS OF INTEGRATION



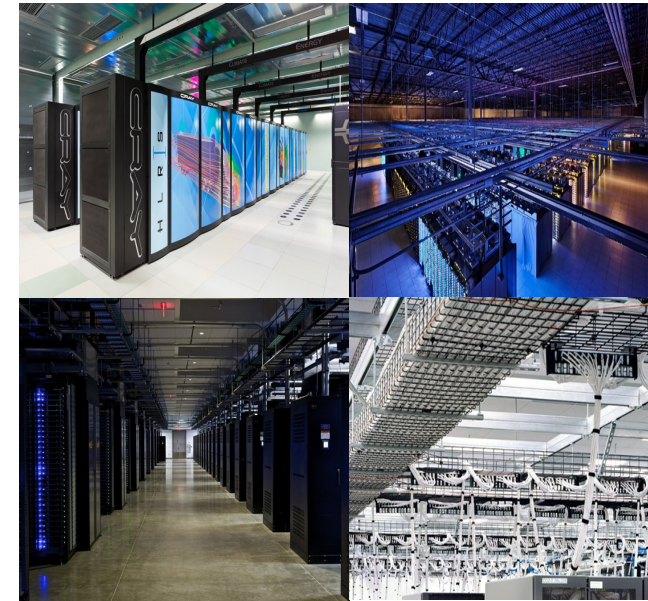
**Facilitating DoD Access:** Create an ecosystem for package-level optical signaling, enabling disruptive advances for artificial intelligence, phased arrays, sensors and processing.



# A slide from the HPC - Data Center TWG Presentation

Acknowledgement: Kanad Ghose Feb 25<sup>th</sup> ,2021

- This TWG focuses on the need, requirements and solutions for realizing **SYSTEM-IN-PACKAGE** that integrate processing elements, accelerators, storage, IO for the following markets:
  - HPC Systems
  - Scale-out Systems
  - Data Centers
  - High-end Networking
- This TWG focuses on the system-level implications related to performance, power management, security, power distribution/conversion issues and others
- Emerging applications demand domain-specific accelerators
  - Analytics/Intelligence on demand
  - Big data processing
  - IoTs and Edge
  - Blockchain processing
- Emerging processing, accelerator and memory technologies, quantum computing driving new system architectures

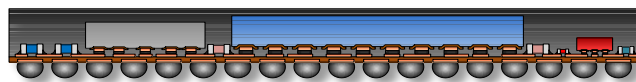




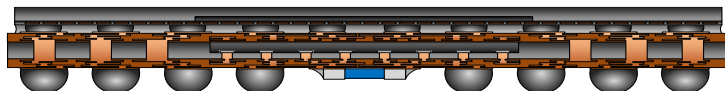
## Fan Out Heterogeneous Package Examples

### 2D & 3D Fan Out Packaging

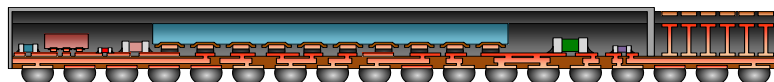
- Chip Last Fan Out SiP



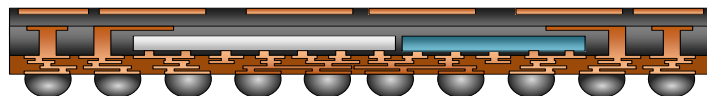
- Double Sided Fan Out POP



- Fan Out SiP with Selective Shielding

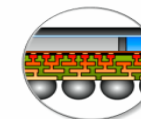
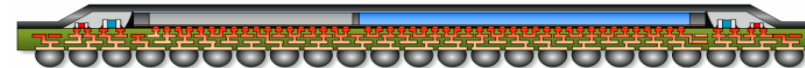


- Fan Out Antenna in Package (AiP)

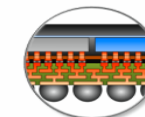
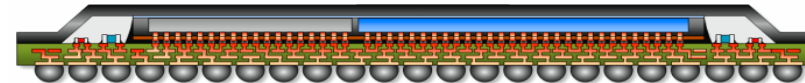


### Hybrid Fan Out on Substrate Variations

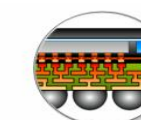
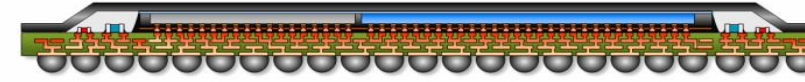
- Chip First Die Down



- Chip First Die Up

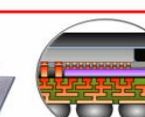
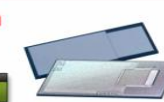


- Chip Last High Density

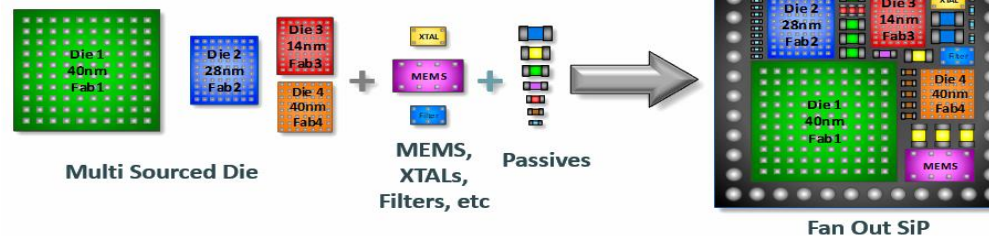


- Chip Last FO w/Bridge

Recent FO Introduction



### Fan Out SiP



# A Page from the HPC - Data Center TWG Presentation

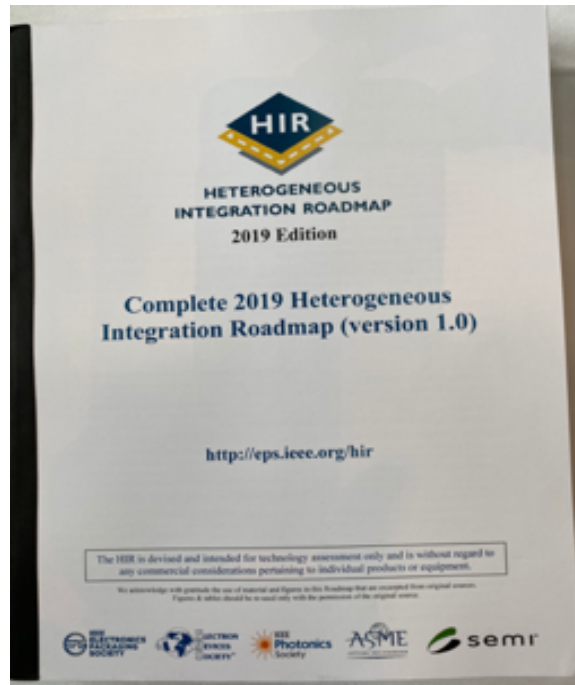
## Acknowledgement: Ken Lanier Feb 25 ,2021

### Test Technology Working Group, Heterogeneous Integration Roadmap Leadership Team

Dave Armstrong & Ken Lanier: Co-Chairmen

2.5D/3D device test	Zoe Conroy	Photonic Test	Dave Armstrong Tom Brown Sylwester Latkowski
Analog and Mixed-signal Test	Don Blair	RF Test	Don Blair
Cost-of-Test	Ken Lanier	System Level Test	Harry Chen
Data Analytics	Ira Leventhal	Specialty Device Test	Wendy Chen
Logic & SOC Device Test	Marc Hutner	Wafer Probe and Device Handling	Jerry Broz
Memory Test	John Caldwell		

**The 2020 update to the test roadmap is output from a team of more than 120 test experts hailing from more than 50 companies world-wide. The leadership team for this effort is shown above.**



Launched 10-10-  
2109

24 chapters

590 Pages

free download

Download Link

<https://eps.ieee.org/technology/heterogeneous-integration-roadmap>

# Heterogeneous Integration Roadmap (HIR)

IEEE Press Release 10-10-2019

PISCATAWAY, N.J.--([BUSINESS WIRE](#))--IEEE, the world's largest technical professional organization dedicated to advancing technology for humanity, today announced the 2019 release of the **Heterogeneous Integration Roadmap (HIR)**, a roadmap to the future of electronics identifying technology requirements and potential solutions. The primary objective is to stimulate pre-competitive collaboration among industry, academia and government to accelerate progress. The roadmap offers professionals, industry, academia and research institutes a comprehensive, strategic forecast of technology over the next 15 years. The HIR also delivers a 25-year projection for heterogeneous integration of emerging devices and materials with longer research-and-development timelines.

- Sponsored by 3 IEEE Societies (EPS, EDS & Photonics) together with SEMI & ASME Electronics & Photonics Packaging Division
- Comprehensively covering microelectronics technology ecosystem
- Articulates state-of-the-art Advances in Technology & Science, Future directions, Significant roadblocks & Potential solutions
- Volunteers (60% industry, 30% Academia, 10% Research Institute)



# Wrap-Up

- Since the HIR release Oct 10, 2019, Heterogeneous Integration Roadmap is making its mark in the global electronics ecosystem. Heterogeneous Integration Roadmap journey is off to a strong start
- ODSA & HIR share common objectives in fostering Chiplet Technology & accelerating Chiplet business implementation
- Packaging technologies for Heterogeneous Integration, serve as the crucial link for the design-build-deliver collaboration between the Wafer Foundry and the System Integrator
- AI & ML across stake holder collaboration & data sharing will build trust & mitigating risk across supply chain.

# Thank You

[william.chen@aseus.com](mailto:william.chen@aseus.com)

Acknowledgement : Heterogeneous Integration Roadmap Technical Working Groups Team

HIR Download link <https://eps.ieee.org/echnology/heterogeneous-integration-roadmap>





# Chiplets in Heterogeneous Acceleration

Business Opportunities and Challenges

Giri Chukkapalli



# Heterogeneous Acceleration

- Computational requirements are growing exponentially,
  - Driven by ML/DL/AI advances
- Application and algorithmic diversity is growing , and
- Loss of general purpose processor perf improvements
  - Due to diminishing Process technology benefits
    - \$/Transistor is increasing
- Architectural innovations to keep pace
  - Resulting in Heterogeneous acceleration
- Potential for Splitting Functional Blocks into Chiplets

# Silicon Design Flow

- 4 year design cycle with a delivery cadence of ~18 months
  - Requiring 1.5X team
- Tape out and Wafer costs, EDA tool costs continue to grow
  - Rightfully due to growing complexities
- ~150k Volume with ~50% margin needed to break even
  - Irrespective of size or complexity of the Chip
- Economies of Scale required often from broader set of Chips
  - Very hard to succeed on a single chip design
- Bottomline: There is little slack in Silicon Business
  - Proof is almost all the current Silicon companies
- **CHIPLETS NEED to improve one or more of the above Business Risks**

# Chiplets: Use Cases, constraints

- Overcome Reticle limit
  - Perf sensitive
  - Functional, symmetric/perf breakup
  - May require parallel D2D interfaces and custom silicon interposer,
- Bringing Board/System into Package
  - Cost sensitive
  - Serial D2D and organic interposer may be sufficient
- Two distinct issues
  - Silicon companies broadly adopting Chiplets even within their own ecosystem
    - If reticle limit is not an issue, does Chiplets truly provide Perf/TCO?
    - Limitations of EDA Tools, Arch/design space exploration tools that take Chiplets into account
  - Relying on third party Chiplets



# Chiplet Tax

- Increased design complexity
- Useful area vs Perimeter area
- Increased Power and latency of On-Die data movement going Off-Die
- Built in redundancy to ameliorate KGD problem
- Increased packaging costs
- Some upfront increased NRE and per Chiplet Tax
- Gov Initiatives and Industry consortium efforts help to establish the Chiplet Ecosystem: DARPA, HIR etc.

# Standards vs Innovation

- Premature standardization can kill innovation
  - Standards are antithetical to innovation?
    - If right boundaries/Interfaces are not chosen
- Standards cannot be least common denominator
- Too many open standards is as if no standard
  - Recent serial interface standards effort is the best example
    - CCIX, GenZ, OpenCAPI
      - Finally some convergence to CXL
        - Any lessons learned?



# SW Ecosystem for Chiplets

- Mechanical, thermal, power delivery and IO standards
  - Chiplet Architecture Definition Language (cADL?)
- Chiplets management, monitoring SW
- Chiplet Debug SW



# Chiplets: Challenges

- Well known Known Good Die (KGD) and all the related issues
- Who owns life time guarantees, Field debug
  - End users may have to share risk atleast initially?
- Risk of relying on a third party Chiplet component for shipping a product
  - Marketplace with multiple choices could solve this problem
    - Chicken and Egg
- Companies of Different Breadth and Depth makes the Chiplet marketplace complicated
  - Key is to reduce risk, cost, time across the whole silicon design flow
  - Real or perceived value transfer could hinder Chiplet marketplace participation

# Chiplets: Opportunities

- Enables separation of Concerns
  - High Complexity, low perf Block can be split off
    - Avoids taping out the whole SoC in case of a bug
    - Can be reused over multiple Gen



# Thank you.

Connect. Collaborate. Accelerate.



**OPEN**  
Compute  
Project®



# Chipllets for the Masses

## Enabling a Vibrant Chiplet Design Ecosystem

### Common language lowers design & cost barriers

#### Standard D2D Interfaces

Different use cases: One size does not fit all

- Parallel & Serial I/F
- Package technology (2D / 2.5D / 3D)
- NoC-to-NoC solution
- Security, Interoperability

#### Unified 2.5D/3D IC Design Environment

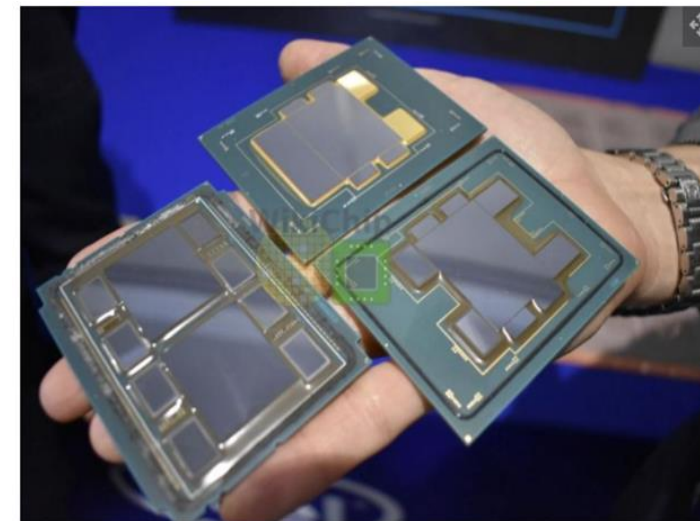
Package / Die co-design and verification tools

- Floor planning / Sims
- Signal & Power Integrity / Thermals

#### Standard Test Infrastructure

KGD & beyond

- Testability for KGD
- Hierarchical intra- & cross-die testability



(Image credit: @david\_schor WikiChip)

### Packaging & Assembly directions

#### Access to Advanced Packaging

3D not for the masses (yet?)

Fanout reduces cost barrier

- Access to “design kit” for design



**OPEN**  
Compute  
Project®

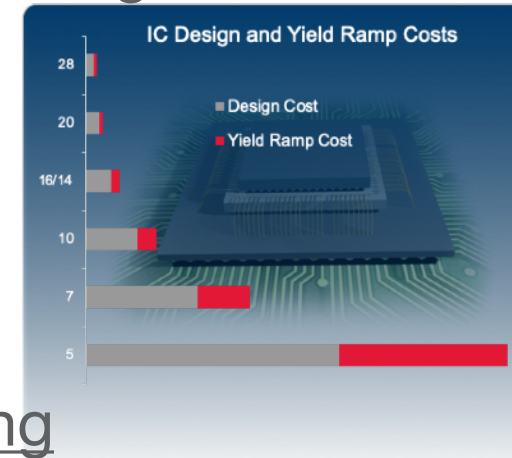
# **Business Consideration for Chiplet based compute products**

Rishi Chugh , Cadence Design



# Business Consideration - Chiplet Based Modular Design

- Leverage SoC design investments across organization to Optimize overall BOM cost
- Optimize investment based off “Node” and “SoC Application” requirement
- Accelerate market adoption by Standardization specific to Chiplet designs :
  - Electrical / Functionality / Features
- Chiplet based design flow for Predictability
  - Methodology / Testability / Integration
- Foundry partner collaboration – Yield & Integration
- Leverage Chiplet design concept for next generation SiP partitioning

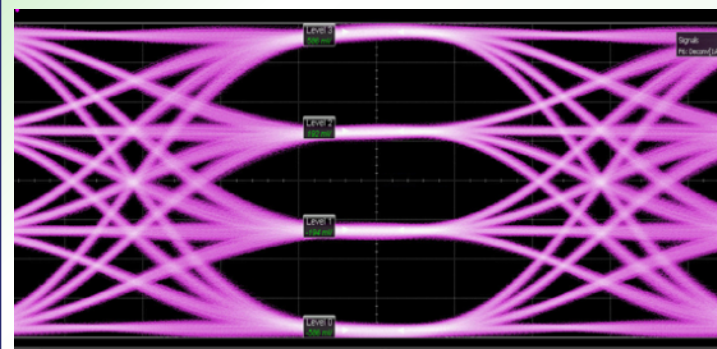
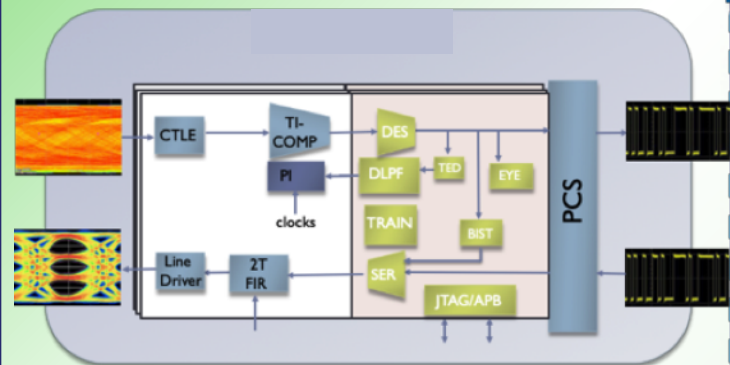






**OPEN**  
Compute  
Project®

# Serial or Parallel?



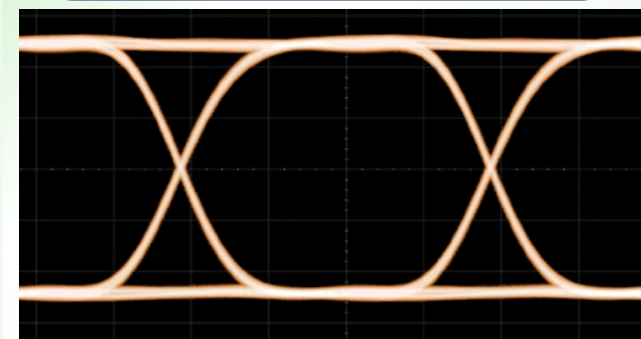
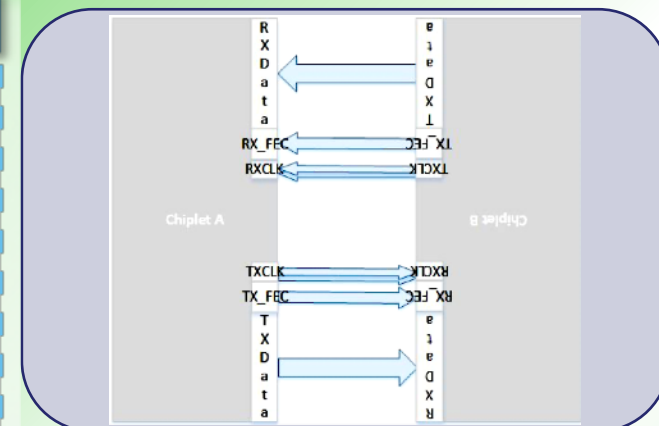
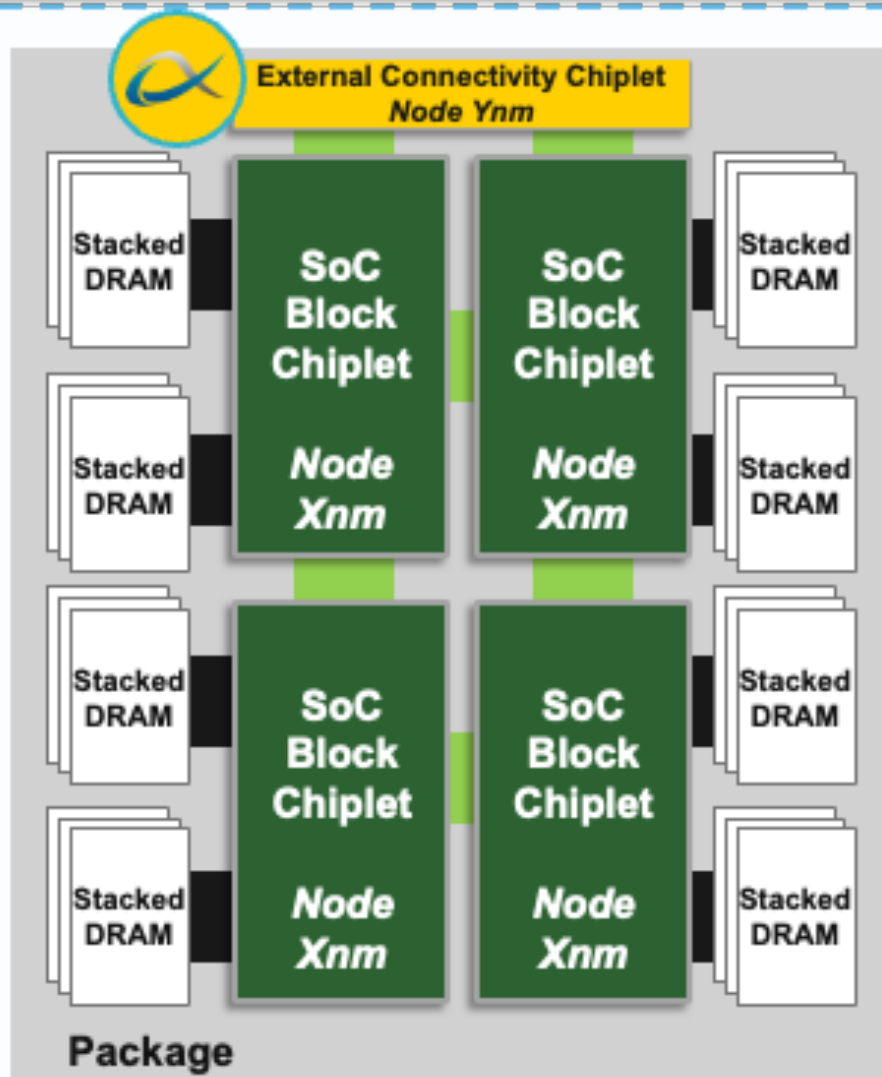
✓ Organic substrates

✓ High Bandwidth

✗ Complex interface

✗ Higher power, latency

## Disintegrated Design with Chiplets



✓ Low power, latency

✓ Simple interface

✗ Requires interposers for high density

✗ Complex routing



# Chiplet Economic Constraints

*--A Builder's Perspective*

*Moderator:* Andreas Olofsson, Zero ASIC

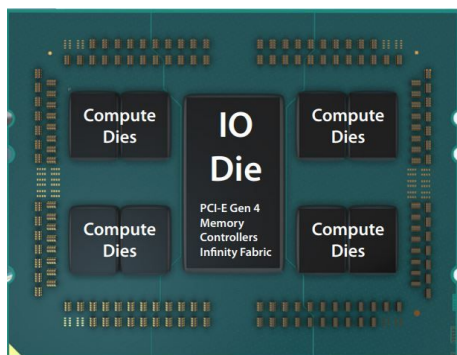
*Panelists:* Eelco Bergman, ASE  
Max (Sunghwan) Min, Samsung  
Regan Mills, Teradyne  
Swami Prasad, JCET



# ODSA Goal Restated



**INTEL**



**AMD**

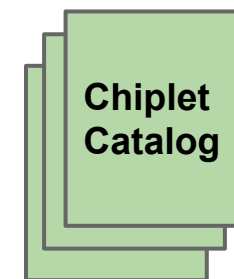


**XILINX**

**Chiplets In Production Today!**  
(...but only in vertically integrated form)



**NEW:** 3rd Party  
Chiplet Players



**Off the Shelf**  
(in storage or  
produced on  
demand)

Product  
Owner

**Secret  
Sauce  
Block  
Design**

**System  
Design**

**Foundry**

**OSAT**

The semiconductor zero sum manufacturing  
game grows from 3 players to 3+N players

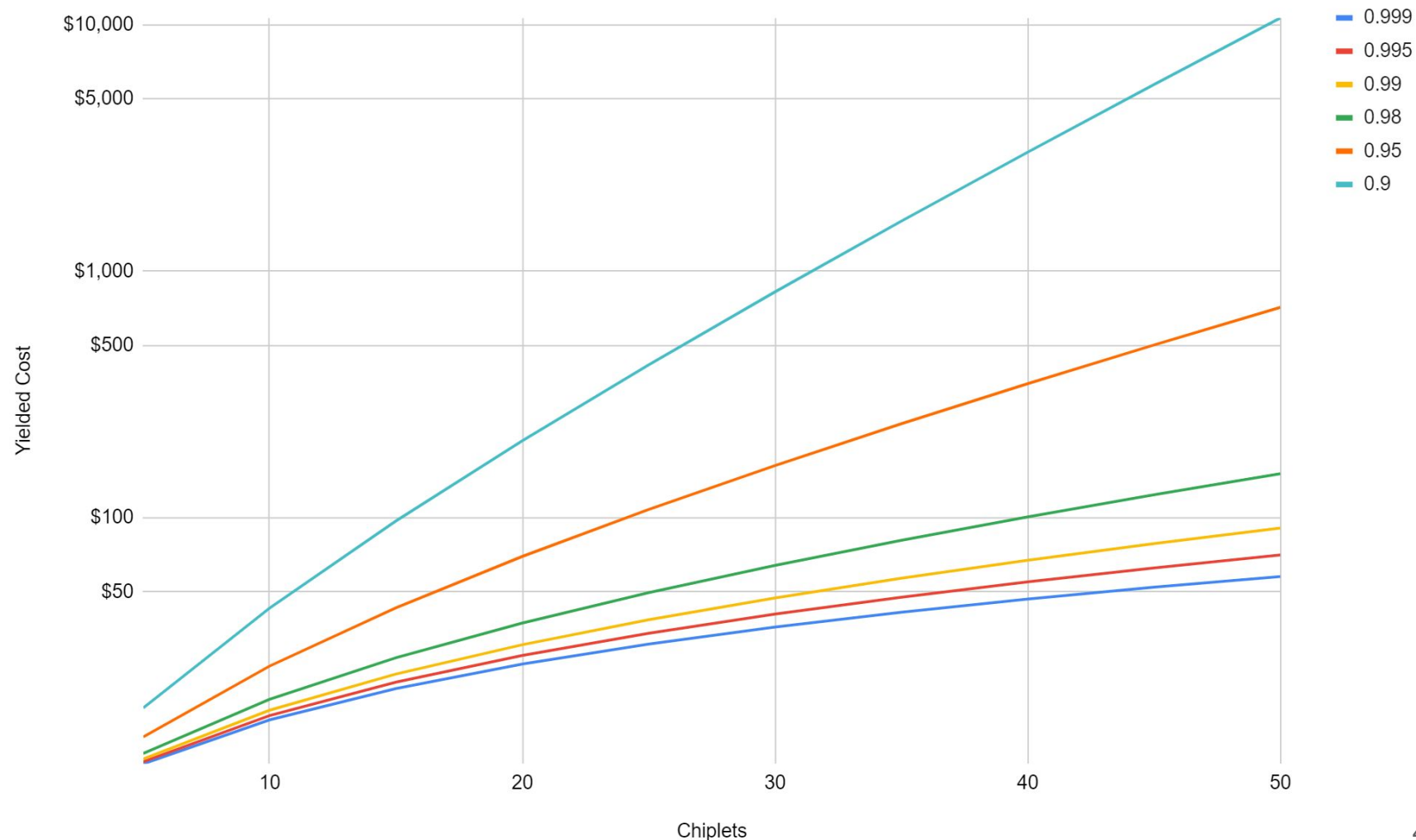


# Builder Business Models

	IP	Foundry	Assembly & Test	PCB Assembly
Input	“ideas”	Raw material Design	Wafers, substrates, interposers, raw materials, test	PCB, packaged parts, raw materials, test program
Output	IP	Wafers	Good parts	Good boards
Market Size	\$5B	\$80B	\$30B	\$4001B
Gross Margin	96%	54%	15%	7%
Setup CostsMargin	0	\$100,000 - \$10M	\$1,000 - \$1M	\$1,000 - \$100,000
Value of Unit Shipped	N/A	1X	1.1X - 2X	2.1X - 4X
Factory Test	N/A	Wafer Acceptance Test	In circuit testing, AOI	In circuit testing, AOI
Design Rules	N/A	Fixed	Variable	Variable
Yield	N/A	10 - 99%	99%	90 - 99%
Bad Unit Cost	N/A	\$0.1 - \$150	\$0.1 - \$1,000	\$1 - \$10,000
Yield Ownership	Customer*	Customer*	Customer*	Customer*
Warranty	Up to license	New Wafers	Variable	Rework/Replacement

# Basic Builder Economics

1. Advanced technology is hard and expensive)
2. Advanced technology & high volume is REALLY hard and expensive
3. Advanced technology & high yield & low cost is “MOORE’S LAW” hard



Model: \$1/chiplet, \$5/assembly



**OPEN**

Compute  
Project®

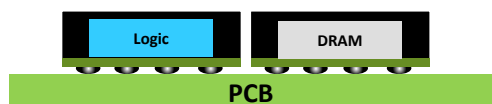
# Foundry View

- Max (Sunghwan) Min, Samsung

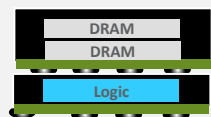


# CUBE for Enabling Chiplet (Samsung Foundry View)

- CUBE is a device (interposer) connecting small and large chiplet(s) horizontally and vertically



(PCB is a device connecting packages)



- + TMV
- + PoP
- + LPDDR (molded chiplet with <0.4mmp)



- + TSV
- + CoW (u-bump)
- + Interposer
- + HBM (molded chiplet with 55ump)



- + Logic TSV
- + D2W Cu-Cu
- + D2D IP
- + Logic chiplet (?)

## CUBE examples

Requirement	Solution
Known good active interposer	HBM2/2E/3 ( <b>HBM CUBE</b> ) Logic on Logic ( <b>X CUBE</b> )
Known good SI interposer	Thinned Si interposer ( <b>I CUBE</b> )
TSV-less known good interposer	RDL interposer ( <b>R CUBE</b> )
Flexible pitch/layer interposer	Embedded bridge ( <b>E CUBE</b> )

## Challenges to be addressed for enabling chiplet

- Heterogeneous (logic A/B + memory 1/2 + D2D  $\alpha/\beta$  + decap + ...) integration with OSAT and IP partners
- Lots of test vehicles (MTV, TTV, FTV, CPI, ...) confirming PPA (W, Hz, mm<sup>2</sup>) feasibility
  - Thermal & mechanical integrity
  - Signal & power integrity
  - Form factor
- Known good chiplet and CUBE (yield)



**OPEN**  
Compute  
Project®

# Assembly & Test

- ASE – Eelco Bergman
- JCET– Swami Prasad
- Teradyne – Regan Mills



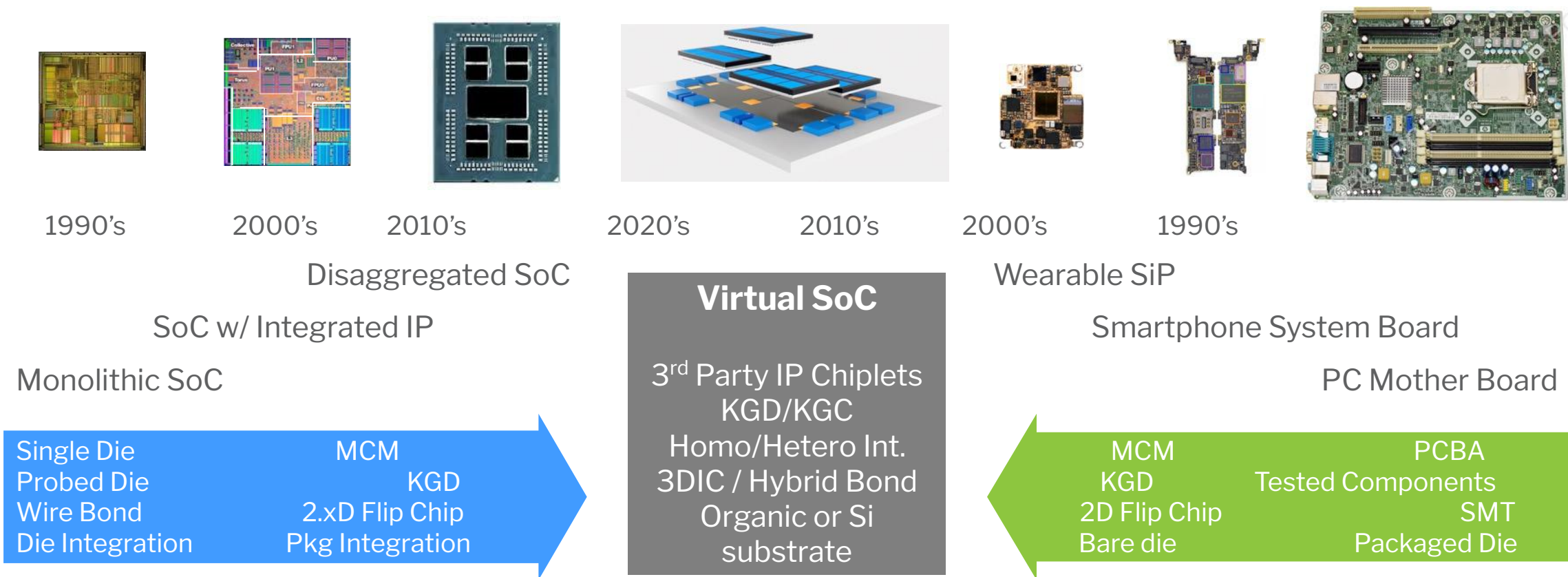
**ASE GROUP**

**JCET**

**TERADYNE**

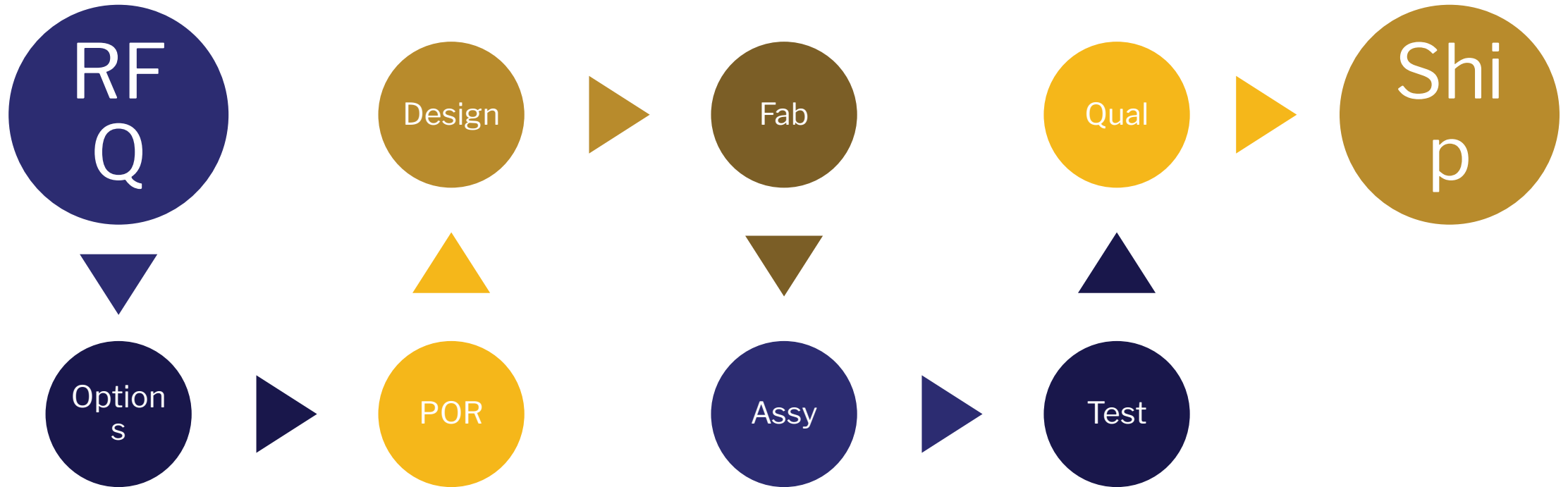
# Converging Solutions & Business Models

## OSAT & EMS



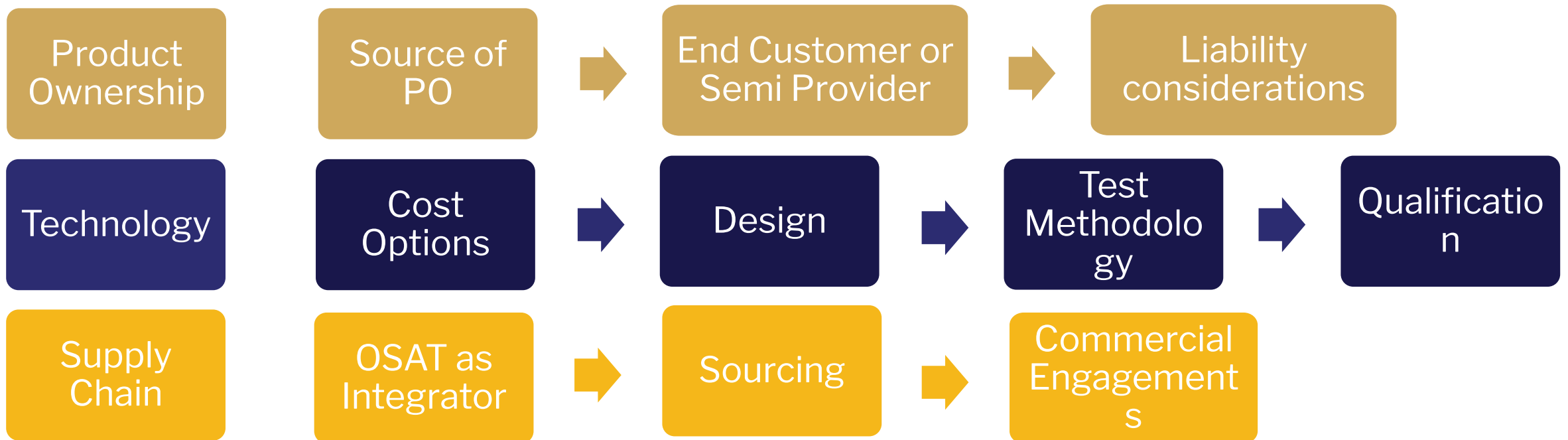


# Single Die/Current Business Flow



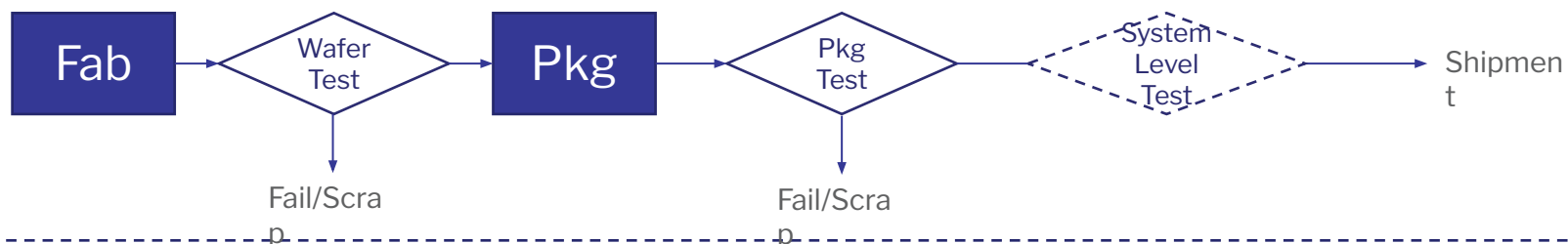
- POR : Package, Test Specs provided by the customer
- Silicon, Memory Package/s are consigned
- Substrate, Passives can be consigned or purchased
- Process Flow - Wafer Sort, Assembly, Final Test/System Level Test

# Chiplet Business Flow



# Value of Quality – A Shift with Chiplets

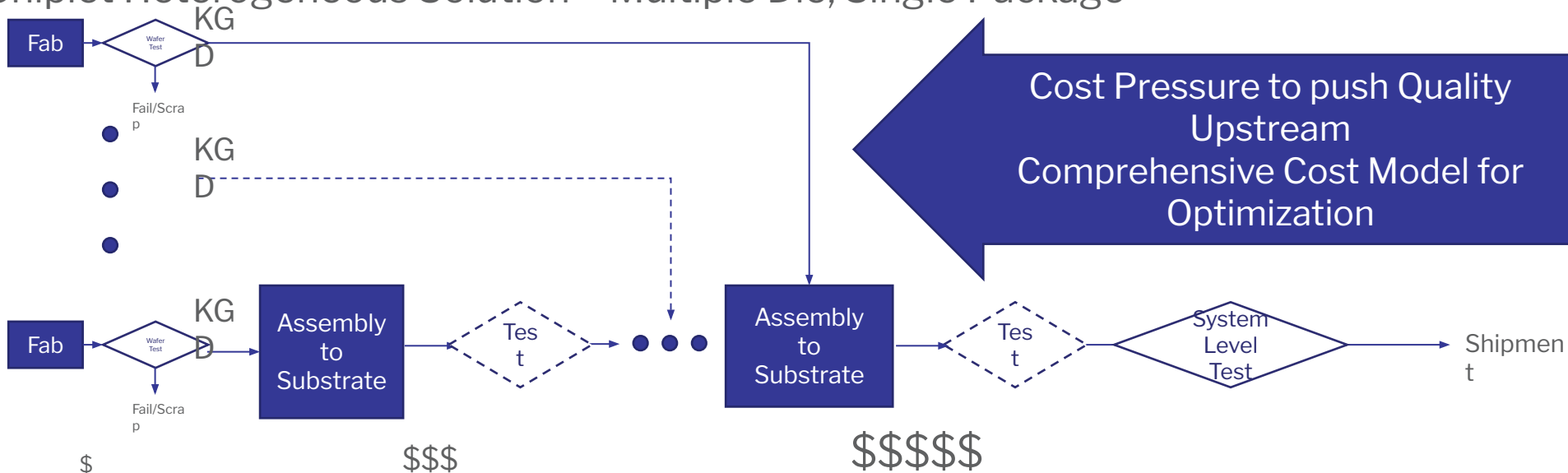
## Monolithic Silicon – Single Die, Single Package



### Cost Factors

- SLT req'd for some devices to achieve AQLs
- Potential to move SCAN in SLT to reduce cost

## Chiplet Heterogeneous Solution – Multiple Die, Single Package



### Cost Factors

- Rapidly accumulating costs as die are mounted
- No/Limited rework capability (different than PCB assembly)
- Cost of bad die drives KGD methodology
- Possible need for intermediate test of assembly to maximize yield at final stage
- Pre-combinations of die (single supplier cubes) viable to reduce the multiplicative impact of yield

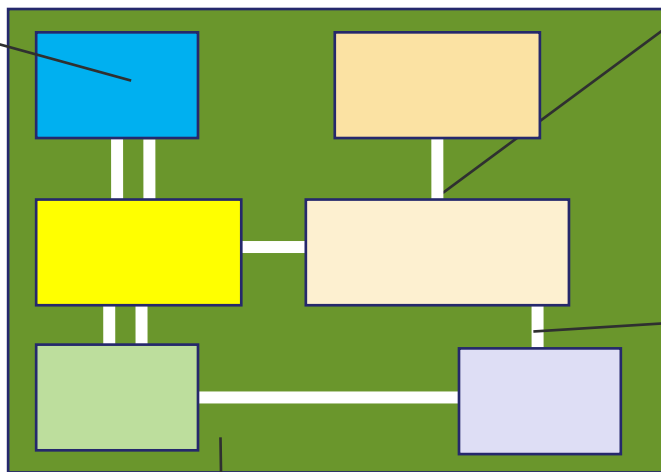


# Chiplet Manufacturing

*Packaging and Test Technical Considerations Directly Impact Economics*

## Quality - Known Good Die

- Who is responsible for quality of die?
- What is the economic model for an escaped bad die? Cost of a simple IP chiplet may be insignificant to the cost of the ruined assembly.
- How to ensure quality of substrate?
- Testability concerns with IP blocks which are designed to be verifiable but not testable in stand-alone manufactured state; additional die area (cost adder) may be required for testability



## Interoperability

- Extension of existing test standards required to allow efficient test setup for interface/interoperability testing
- Industry adoption of test standards will drive test costs down

## High Speed Interfaces

- Driver strength limited for cost reasons, need test bumps and drivers
- Die loopback & adequate design margin for economic wafer test to support KGD
- HBM-like redundancy viable in some cases

## High Speed Interconnects

- Substrate a key part of system performance => is substrate test required?
- Full system level test likely required to find 2<sup>nd</sup> order interactions between die and substrate -> full system simulation environment key to yield at EOL



**OPEN**  
Compute  
Project®

# Thank You

Connect. Collaborate. 13  
Accelerate.

# Deliver / Business Panel

- Moderator: Dave Greenfield - Intel
- **System Integrator**  
Microchip: Anu Ramamurthy  
Marvell: Ramin Frajadrad
- **End Users**  
Google: Ben Kerr  
Alibaba: Weifeng Zhang  
FB: Nicolaas Viljoen  
Microsoft: Ishwar Agarwal



# Chiplet Business Collaboration

Dave Greenfield – Intel Corporation

Connect. Collaborate. Accelerate.



**OPEN**  
Compute  
Project®

# Agenda

- What's the problem?
- Scope the opportunity
- Case Study: identify key challenges
- Additional “learning



# Value in Wireless Radio – 25% Lower System Power

10-20x reduction (50W - 100W) reduction in interface power

## Use Case I/O Power Example

Parameter	Sub-6GHz NR
RF frequency	3.5-6GHz
Number of TR	64T/64R <sup>1</sup>
IBW (MHz)	200
JESD204C lanes <sup>2</sup>	53
JESD power now (W) <sup>3</sup>	106
JESD power future(W) <sup>3</sup>	53
AIB power now (W) <sup>4</sup>	5.3



*Power is too high*

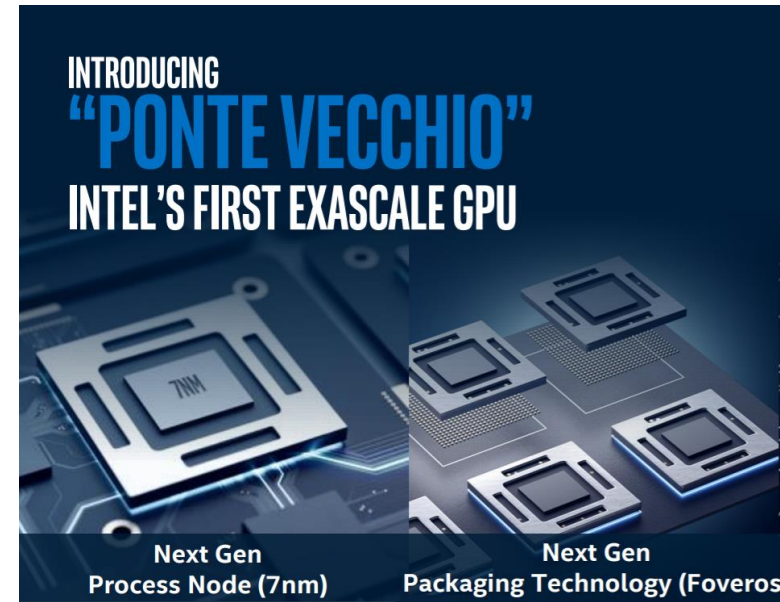
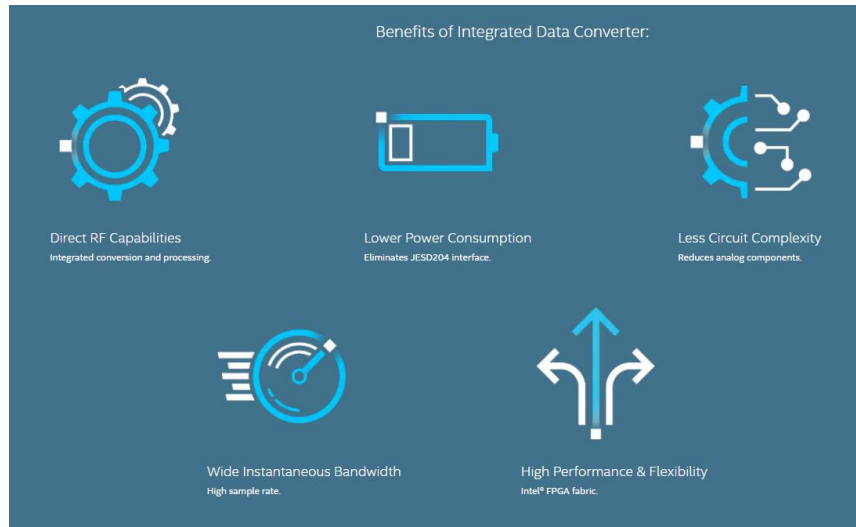
There must be a **compelling** reason to use MCP vs. discrete option!

Connect. Collaborate. Accelerate.



# Intel Disaggregated Design

- Intel developed POC with DARPA CHIPS program partnering with external supplier
- Intel released analog FPGA technology announcement in Q4-2020 to enable future products
- Intel Programmable Solutions Group (Altera) leader is disaggregation strategy



- <https://www.intel.com/content/www/us/en/architecture-and-technology/programmable/analog-rf-fpga.html>  
Connect. Collaborate. Accelerate.

# Business Case for MCP

- What's the cost to productize the MCP (probably not 6-digit cost)?
  - Who's doing the work?
  - How extensive is validation work?
  - How many units needed for volume validation?
- Do the chiplets exist (off-the-shelf vs. development project)?
  - Significantly different set of challenges if 2<sup>nd</sup> party needs to develop new chiplet
  - Why bring in development partner?
- What's the market opportunity?
  - Size the market, assess the risk, estimate time to productize . . .



# FPGA Case Study

- How do we share the revenue?
- How handle IP ownership?
- How address supplier risk (acquisition / continuity of supply)?
- How connect with supply team?
- How address funding challenge (development & productization)?



# The “Deal”

- Key Term Sheet Details
  - NRE to accelerate product development
  - KGD deal with escrow provisions
  - IP: define ownership & license rights
  - Define exclusivity terms
  - Define impact of schedule delays (who takes on product risk)?
  - What if known **good** die isn't actually **good**? Yield fallout (chiplet could be low % of high MCP cost) – define acceptable defect density & resulting terms?

# Extra Provisions (Stuff We Learned Along the Way)

- Units for test (need a large amount of die) – who pays & what price?
- Who owns IP rights to packaging IP between chiplets?
- How much uncertainty on technical issues with SOW can we live with?

# Summary

- Find a pathfinding opportunity for business model and KGD exploration
- Easier to deal with revenue sharing challenges in market where there is ample margin to share than in cost sensitive market
- Identify a compelling technology solution (size, weight, power, cost, yield . . .) vs. finding a market that wants to save area



# Chiplet Business Enablement 'Deliver Panel'

Anu Ramamurthy – Microchip Technology

March 2021

Connect. Collaborate. Accelerate.



**OPEN**  
Compute  
Project®

# Chiplet Business Problems to Solve

## Cost Reduction

- Re-use existing silicon
- Reduce R&D cost
- Fast product SKU development

## Standardization

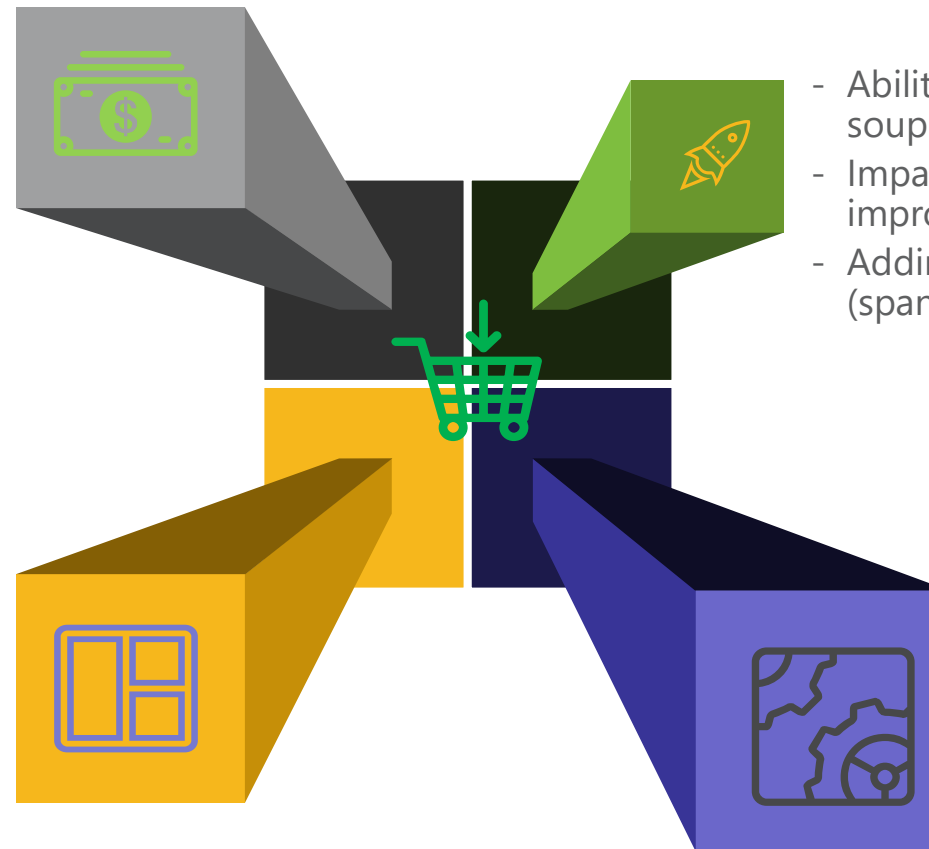
- D2D interface supporting variety of packaging options
- Pin templates for multi-vendor integration

## Fast Innovation

- Ability to innovate at different process nodes – no soup to nuts in 3nm
- Impact operation costs via smaller die and improved yields
- Adding 3<sup>rd</sup> party IP into Microchip IP library (spanning 300nm-6nm)

## Operations

- Agreed upon KGD tests to allow foundries to ship to OSATs for assembly and integration
- Common security protocols across supply chain
- Solid Supply chain



Allows for more players in the market and creates a viable ecosystem

Connect. Collaborate. Accelerate.





# Delivering Chiplet-based Products

Ramin Farjadrad

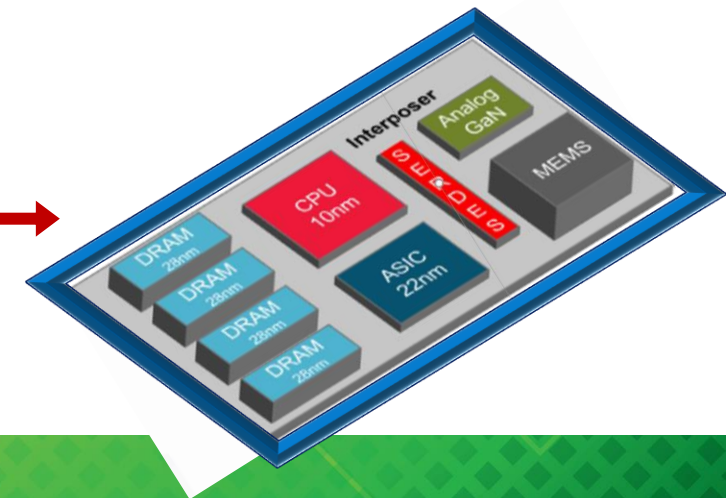
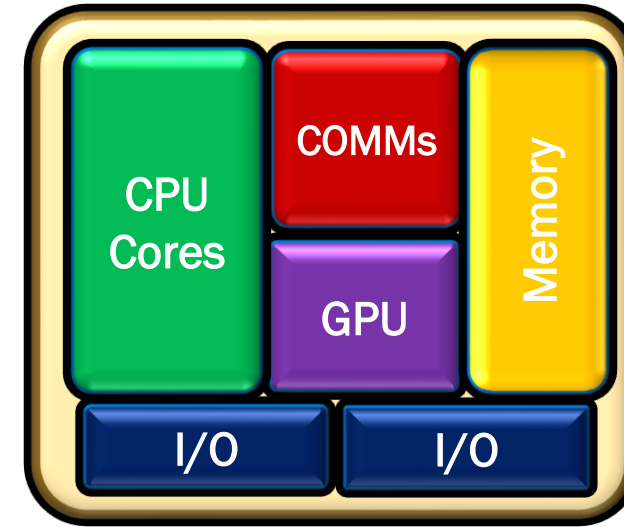
CTO & VP of Automotive/Networking PHYs

Marvell



# Chiplet-based use cases

- **Large SoC Disaggregation**
  - Partition large die to improve yield
  - Reduce development cost & time-to-market
  - Use optimized process technology per functions
- **System-in-Package (SiP)**
  - Higher performance systems
  - Smaller footprint
  - Lower power



# Building systems with chips vs chiplets

Chiplet-based Systems can be built similar to systems with Chips today

## — Conventional System OEMs

- Receive good Chips screened at production test
- Connect good Chips together with **Interoperable Standard interfaces\***
  - **PHY Layer:** PCIe, DDR Bus
  - **MAC Layer:** CXL, DDR Controller
- Test the final system

## — System-in-Package OEMs

- Receive known-good-die (KGD) screened at wafer test
- Connect KGD Chiplets together with **Interoperable Standard interfaces\***
  - **PHY Layer:** XSR, BoW, HBM
  - **MAC Layer:** AXL, CXL, HBM Controller
- Test the final System in Package (SiP)

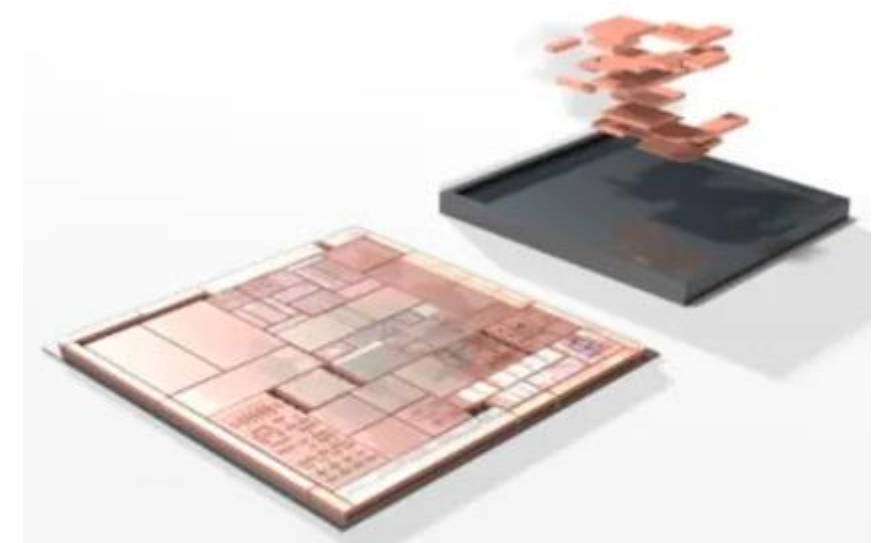
\* Proprietary interfaces are perfect options for vertical integration/Captive Systems



Connect. Collaborate. Accelerate.

# Interface routability is the KEY

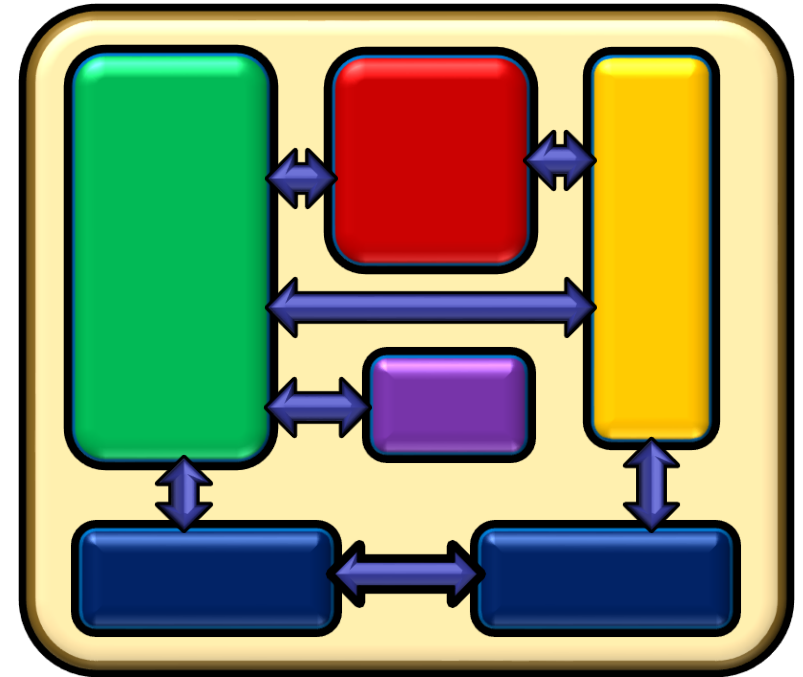
- Without D2D routability, all Chiplets need to perfectly match side by side
  - Cannot have **one-size-fit-all** Chiplets
    - Exceptions: New ASICs that can be designed to fit nicely with all Chiplets
- Proper D2D routability is required to enable SiP implementation with off-the-shelf Chiplets
  - Chiplets-based SiPs should have PHYs with reasonable reach (~1 inch)
    - Similar to conventional systems,



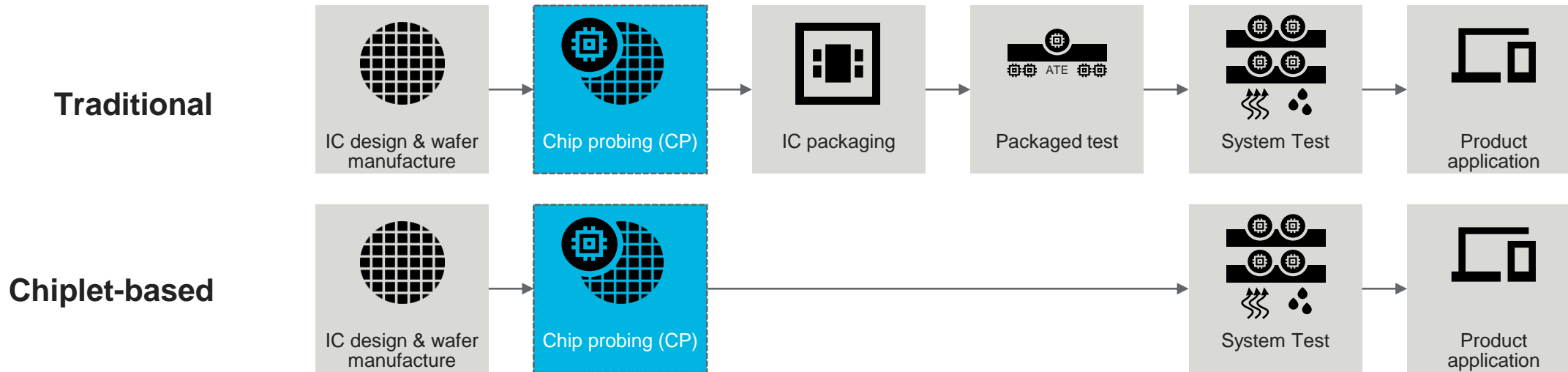


# Interface routability is the KEY

- Without D2D routability, all Chiplets need to perfectly match side by side
  - It defines the purpose of Chiplet-based systems, if we need to build several Chiplets per function with different dimensions optimized for target system
  - Exceptions: New ASICs that can be designed to fit nicely with all Chiplets
- Proper D2D routability is required to enable SiP implementation with off-the-shelf Chiplets
  - Similar to conventional systems, Chiplets-based SiPs should have PHYs with reasonable reach (~1 inch)



# High-coverage screening is a necessity



## — Chiplet screening challenge

- KGD screening must happen at Wafer level
- Wafer-level test coverage must be high
  - Yield target >99%

## — The $\mu$ -bump challenge:

- Wafer probe limitations with  $\mu$ -bump limits screening coverage
- High-speed interconnect coverage
  - At-speed full-link test not possible

# Summary

- **Chiplets can be potentially marketed/sold like traditional Chips**
- **Similar key processes need to exist**
  - Standardization of Interface for Inter-Chiplet links
  - Routability of links for practical Chiplet placements
  - Wafer-level screening with high defect coverage
    - A challenge for Chiplets with  $\mu$ -bumps
- **Support to be similar to today's SoC/System model. SiP vendors**
  - will be responsible to support their direct customers
  - work with their Chiplet providers to resolve their SiP issues



# ODSA End User Session

Alibaba, Facebook, Google, Microsoft

Connect. Collaborate. Accelerate.



**OPEN**  
Compute  
Project®



# Disclaimer

SLIDE CONTENT REPRESENTS THE COLLECTIVE VIEW OF ALL ODSA  
END USER WORK GROUP MEMBERS, AND DOES NOT REPRESENT THE  
POSITION OF ONE SPECIFIC MEMBER.



# Enabling a Chiplet Marketplace

- The Need for Chiplets
- “Gaps” and “Gives”
  - Business and Commercial
  - Technical
  - Software and Management
- Chiplet Opportunity



# The Need for Chiplets

- Critical system IPs are not scaling at the same pace as logic
- Large, monolithic die yield badly
- Fab cycles are longer at advanced nodes
- Faster time-to-market leveraging proven chiplets
- Clear need to **enable a chiplet marketplace ecosystem**

# Business and Commercial

Gaps	Gives
<ul style="list-style-type: none"><li>● Multi-source die available from &gt;1 supplier</li><li>● Supply chain guarantees</li><li>● OSAT complexity, inventory, availability and capacity</li><li>● Business model innovation</li></ul>	<ul style="list-style-type: none"><li>● Known-Good Die (KGD) supply model</li><li>● Broad IP availability</li><li>● Established distribution channels</li></ul>

# Technical

## Gaps

- Open Chiplet Specification (work in progress)
  - Common die footprints with multiple form-factors
  - Die-to-die interfaces
    - ODSA BoW and OpenHBI physical layer
  - Protocol adapters
  - Datasheet parameters
  - Design collateral
- Reference designs for characterization and interoperability



# Software and Management

Gaps	Gives
<ul style="list-style-type: none"><li>● Robust and secure chiplet discovery mechanism</li><li>● Chiplet telemetry data</li><li>● Managing package-level resources</li></ul>	<ul style="list-style-type: none"><li>● Simple out-of-band hardware interface</li><li>● Open management interface and protocol</li><li>● Common, extensible management API</li></ul>
Open Chiplet Specification	

# End-User Chiplet Applications

- BoW to PCI-Express
  - External interface and self-contained end-point ([backup](#))
- BoW to many other high-speed interfaces
  - Usage in data-comms (LAN & WAN), tele-comms (5G/OpenRAN), proprietary intra- and inter-rack comms
- Enabling system expansion through SKU modularity
- Advanced interconnect solutions

# Chiplet Opportunity

- Chiplet marketplace TAM is potentially very large
- “Gives” are well understood and there are many development threads are in flight within ODSA
- “Gaps” are solvable - the industry already knows how to do this
  - Open Chiplet Specification
- The chiplet marketplace ecosystem momentum is building...

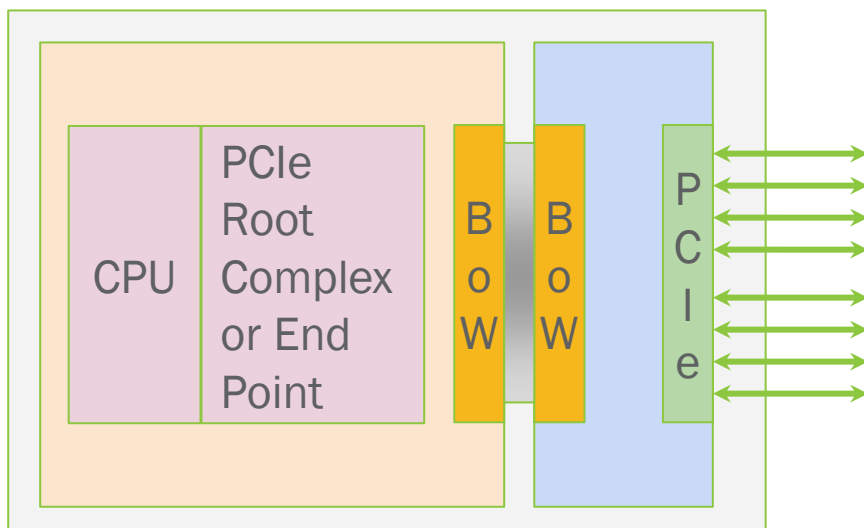


# Backup

Available for reference during panel session

# PCI-Express Chiplet Solutions

## #1: PCIe PHY



## #2: PCIe Expansion

